OptiMOS™ Power-MOSFET

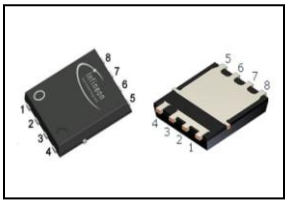
Features

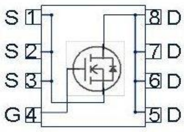
- Optimized for synchronous rectification
- 100% avalanche tested
- Superior thermal resistance
- N-channel
- Qualified according to JEDEC[1)] for target applications
- Pb-free lead plating; RoHS compliant
- Halogen-free according to IEC61249-2-21
- Higher solder joint reliability due to enlarged source interconnection

Product Summary

V_{DS}	60	V
$R_{DS(on),max}$	1.6	mΩ
I_D	100	A
Q_{OSS}	81	nC
Q_G(0V..10V)	71	nC

PG-TDSON-8 FL
enlarged source interconnection





Pb-Free RoHS Halogen-Free

Type	Package	Marking
BSC016N06NS	PG-TDSON-8 FL	016N06NS

Maximum ratings, at T_j=25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	I_D	V_{GS}=10 V, T_C=25 °C	100	A
		V_{GS}=10 V, T_C=100 °C	100	
		V_{GS}=10 V, T_A=25 °C, R_{thJA}=50 K/W[2)]	30	
Pulsed drain current[3)]	$I_{D,pulse}$	T_C=25 °C	400	
Avalanche energy, single pulse[4)]	E_{AS}	I_D=50 A, R_{GS}=25 Ω	380	mJ
Gate source voltage	V_{GS}		±20	V

[1)] J-STD20 and JESD22

[2)] Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm^2 (one layer, 70 µm thick) copper area for drain connection. PCB is vertical in still air.

[3)] See figure 3 for more detailed information

[4)] See figure 13 for more detailed information

Maximum ratings, at T_j=25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Power dissipation	P_{tot}	T_C=25 °C	139	W
		T_A=25 °C, R_{thJA}=50 K/W	2.5	
Operating and storage temperature	T_j, T_{stg}		-55 ... 150	°C
IEC climatic category; DIN IEC 68-1			55/150/56	

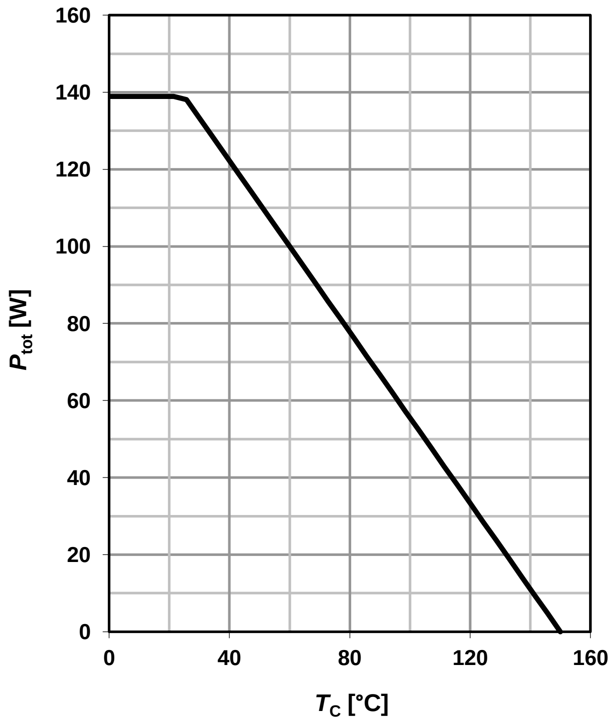
Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Thermal characteristics						
Thermal resistance, junction - case	R_{thJC}	bottom	-	-	0.9	K/W
		top	-	-	20	
Device on PCB	R_{thJA}	6 cm^2 cooling area[2)]	-	-	50	
Electrical characteristics, at T_j=25 °C, unless otherwise specified						
Static characteristics						
Drain-source breakdown voltage	$V_{(BR)DSS}$	V_{GS}=0 V, I_D=1 mA	60	-	-	V
Gate threshold voltage	$V_{GS(th)}$	V_{DS}=V_{GS}, I_D=95 µA	2.1	2.8	3.3	
Zero gate voltage drain current	I_{DSS}	V_{DS}=60 V, V_{GS}=0 V, T_j=25 °C	-	0.5	1	µA
		V_{DS}=60 V, V_{GS}=0 V, T_j=125 °C	-	10	100	
Gate-source leakage current	I_{GSS}	V_{GS}=20 V, V_{DS}=0 V	-	10	100	nA
Drain-source on-state resistance	$R_{DS(on)}$	V_{GS}=10 V, I_D=50 A	-	1.4	1.6	mΩ
		V_{GS}=6 V, I_D=12.5 A	-	1.9	2.4	
Gate resistance	R_G		-	1.9	2.9	Ω
Transconductance	g_{fs}	$\|V_{DS}\|>2\|I_D\|R_{DS(on)max}$, I_D=50 A	70	140	-	S

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Dynamic characteristics						
Input capacitance	C_{iss}	V_{GS}=0 V, V_{DS}=30 V, f=1 MHz	3900	5200	6500	pF
Output capacitance	C_{oss}		900	1200	1500	
Reverse transfer capacitance	C_{rss}		14	48	96	
Turn-on delay time	$t_{d(on)}$	V_{DD}=30 V, V_{GS}=10 V, I_D=30 A, $R_{G,ext}$=1.6 Ω	-	19	38	ns
Rise time	t_r		-	9	18	
Turn-off delay time	$t_{d(off)}$		-	35	70	
Fall time	t_f		-	9	18	
Gate Charge Characteristics[5)]						
Gate to source charge	Q_{gs}	V_{DD}=30 V, I_D=50 A, V_{GS}=0 to 10 V	16	22	30	nC
Gate charge at threshold	$Q_{g(th)}$		10	14	19	
Gate to drain charge	Q_{gd}		8.8	13	20	
Switching charge	Q_{sw}		14	21	30	
Gate charge total	Q_g		58	71	95	
Gate plateau voltage	$V_{plateau}$		3.7	4.3	4.9	V
Gate charge total, sync. FET	$Q_{g(sync)}$	V_{DS}=0.1 V, V_{GS}=0 to 10 V	49	62	86	nC
Output charge	Q_{oss}	V_{DD}=30 V, V_{GS}=0 V	60	81	102	
Reverse Diode						
Diode continuous forward current	I_S	T_C=25 °C	-	-	100	A
Diode pulse current	$I_{S,pulse}$		-	-	400	
Diode forward voltage	V_{SD}	V_{GS}=0 V, I_F=50 A, T_j=25 °C	-	0.9	1.2	V
Reverse recovery time	t_{rr}	V_R=30 V, I_F=50A, di_F/dt=100 A/µs	24	61	98	ns
Reverse recovery charge	Q_{rr}		39	78	156	nC

5) See figure 16 for gate charge parameter definition

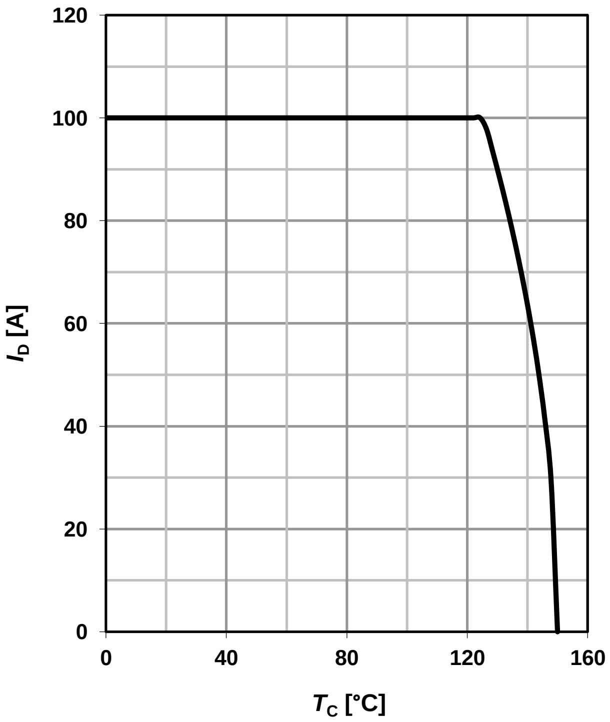
1 Power dissipation

P_{tot}=f(T_C)



2 Drain current

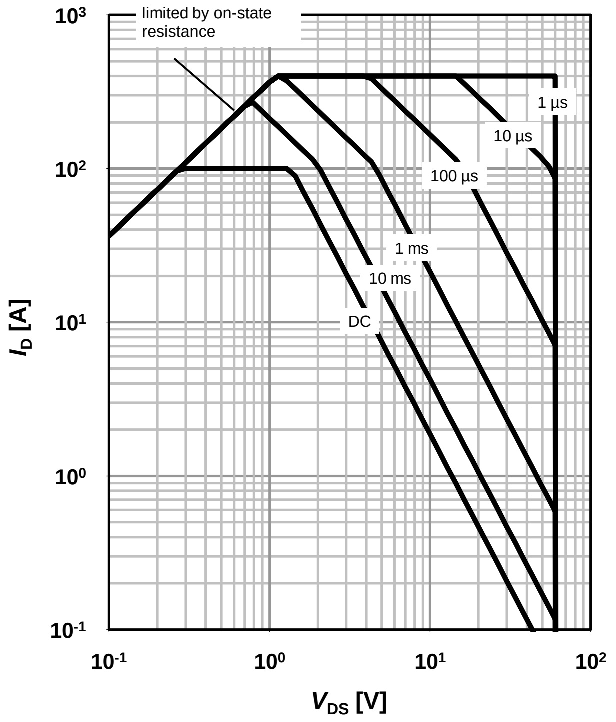
I_D=f(T_C); V_{GS}≥10 V



3 Safe operating area

I_D=f(V_{DS}); T_C=25 °C; D=0

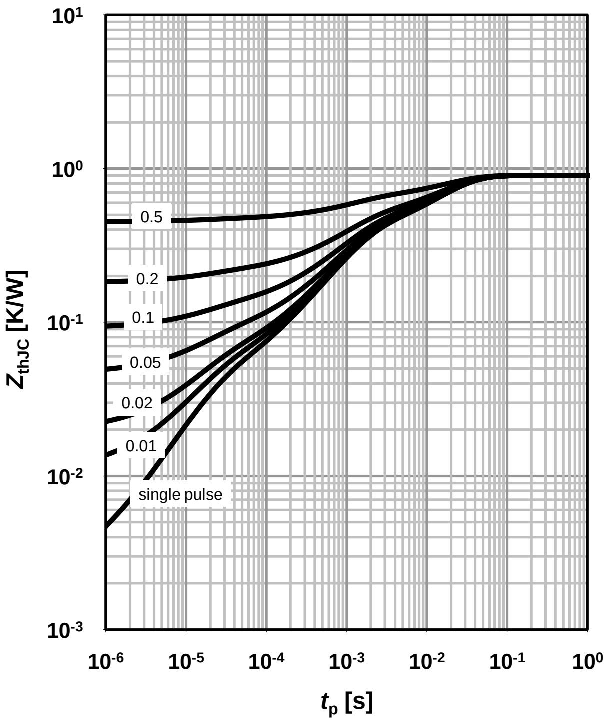
parameter: t_p



4 Max. transient thermal impedance

Z_{thJC}=f(t_p)

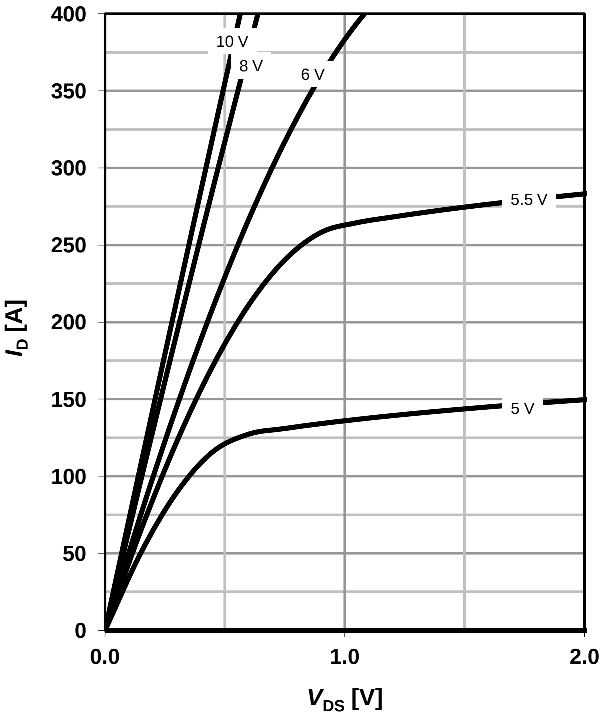
parameter: $D=t_p/T$



5 Typ. output characteristics

I_D=f(V_{DS}); T_j=25 °C

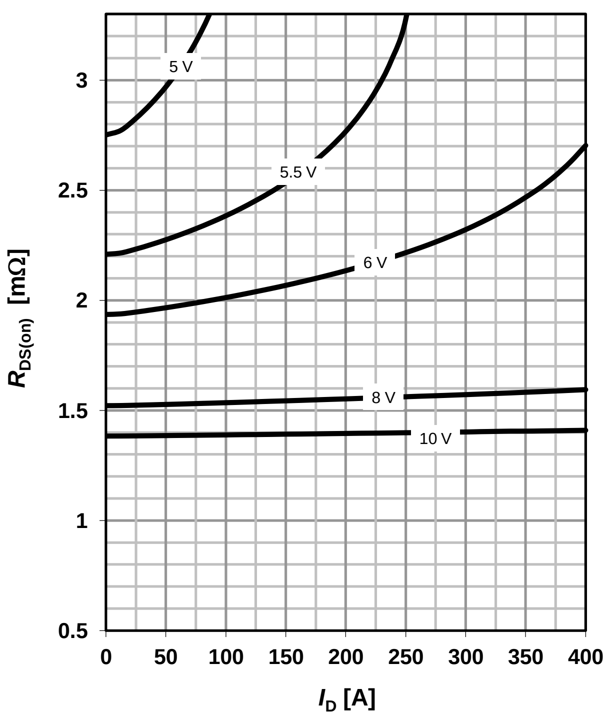
parameter: V_{GS}



6 Typ. drain-source on resistance

$R_{DS(on)}$=f(I_D); T_j=25 °C

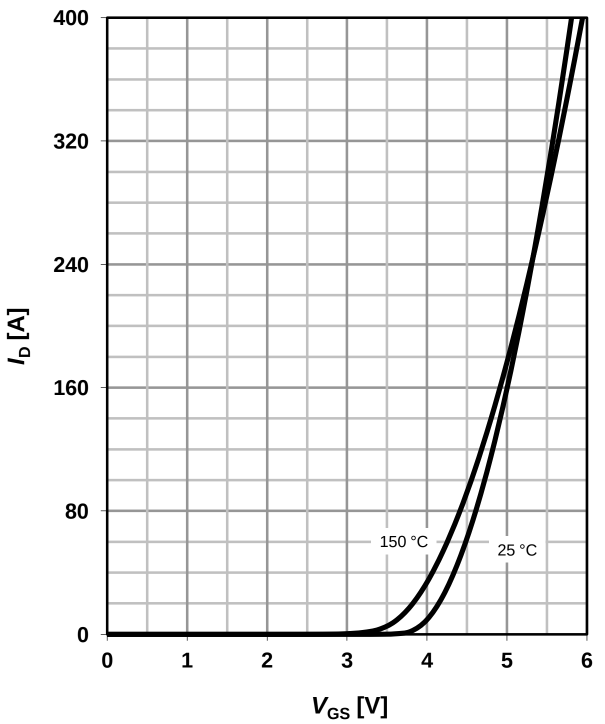
parameter: V_{GS}



7 Typ. transfer characteristics

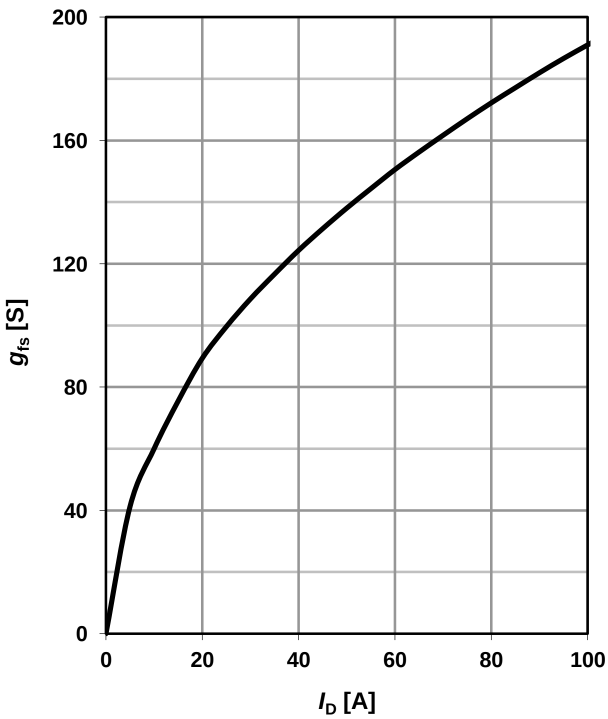
I_D=f(V_{GS}); |V_{DS}|>2|I_D|$R_{DS(on)max}$

parameter: T_j



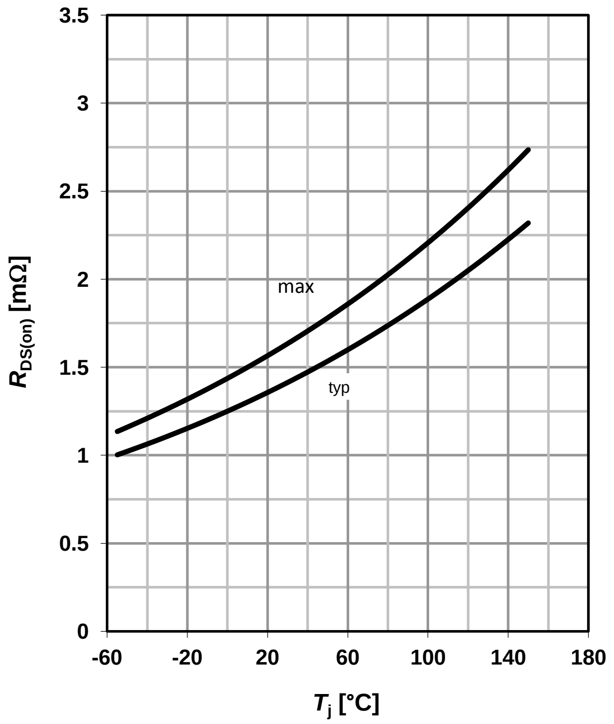
8 Typ. forward transconductance

g_{fs}=f(I_D); T_j=25 °C



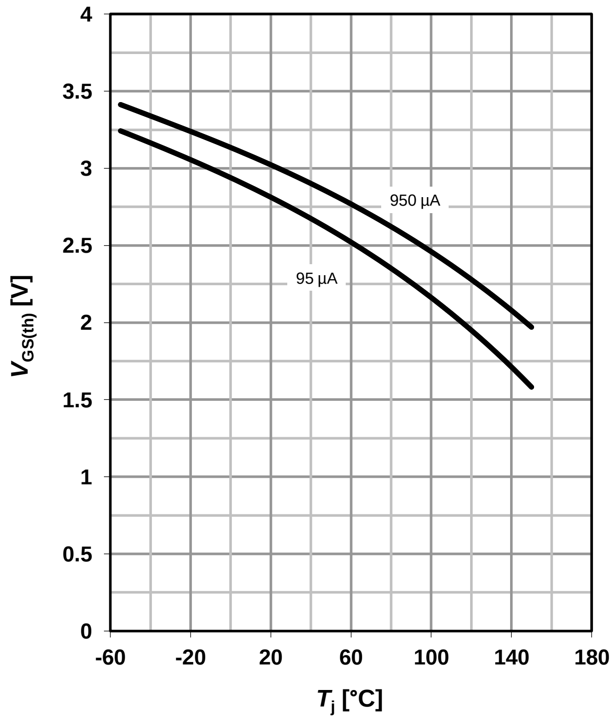
9 Drain-source on-state resistance

$R_{DS(on)}$=f(T_j); I_D=50 A; V_{GS}=10 V



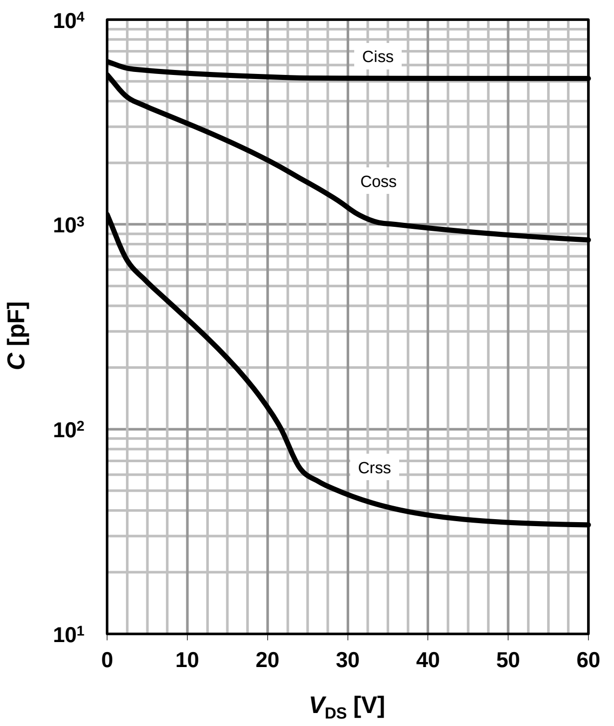
10 Typ. gate threshold voltage

$V_{GS(th)}$=f(T_j); V_{GS}=V_{DS}



11 Typ. capacitances

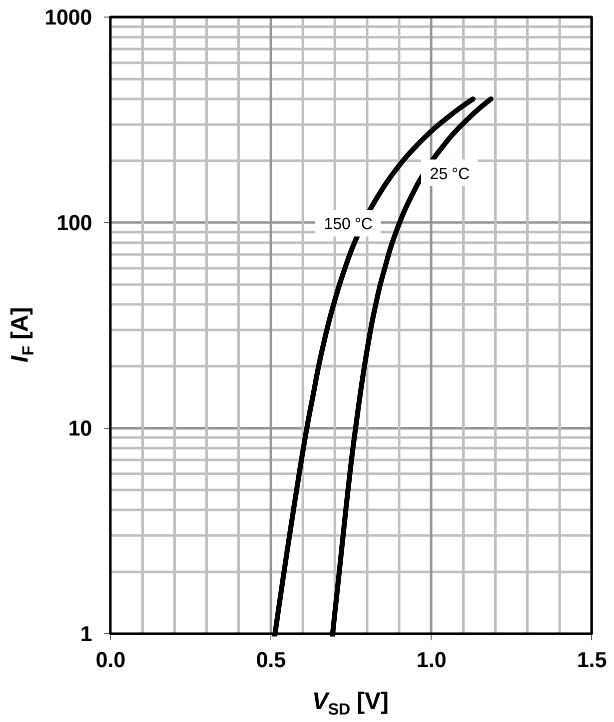
C=f(V_{DS}); V_{GS}=0 V; f=1 MHz



12 Forward characteristics of reverse diode

I_F=f(V_{SD})

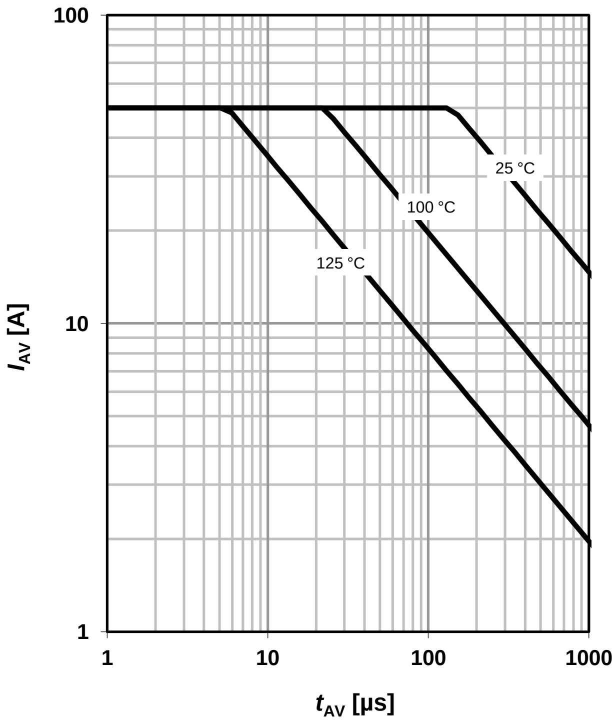
parameter: T_j



13 Avalanche characteristics

I_{AS}=f(t_{AV}); R_{GS}=25 Ω

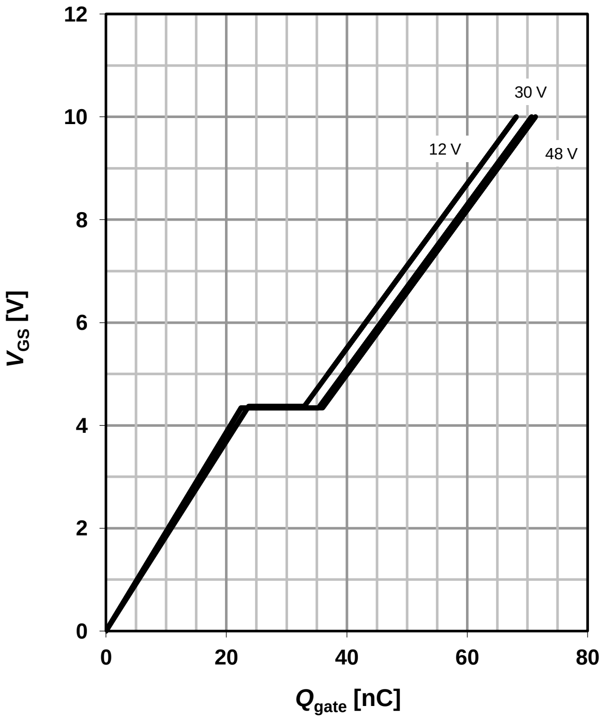
parameter: $T_{j(start)}$



14 Typ. gate charge

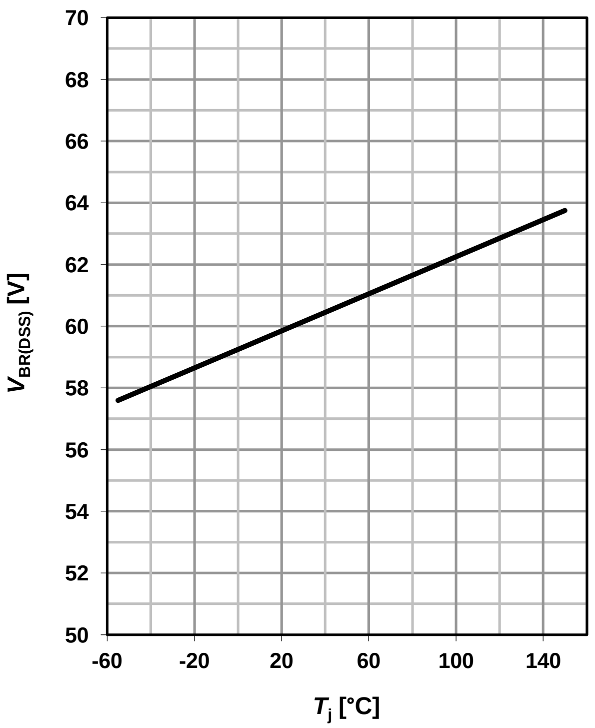
V_{GS}=f(Q_{gate}); I_D=50 A pulsed

parameter: V_{DD}

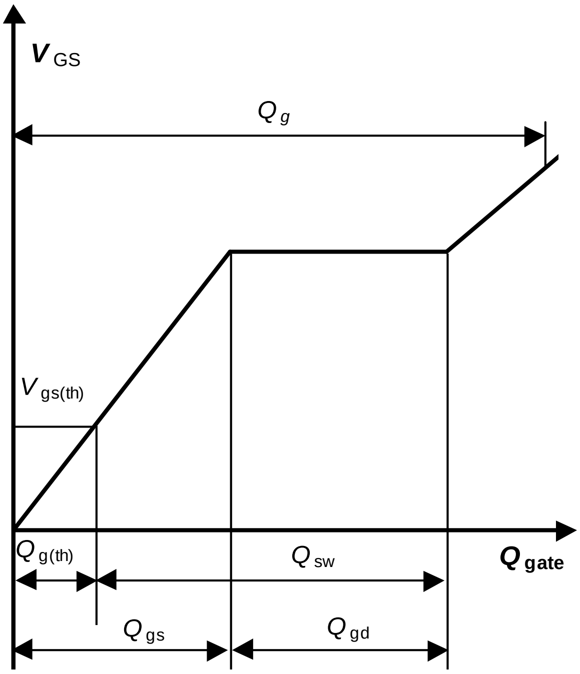


15 Drain-source breakdown voltage

$V_{BR(DSS)}$=f(T_j); I_D=1 mA

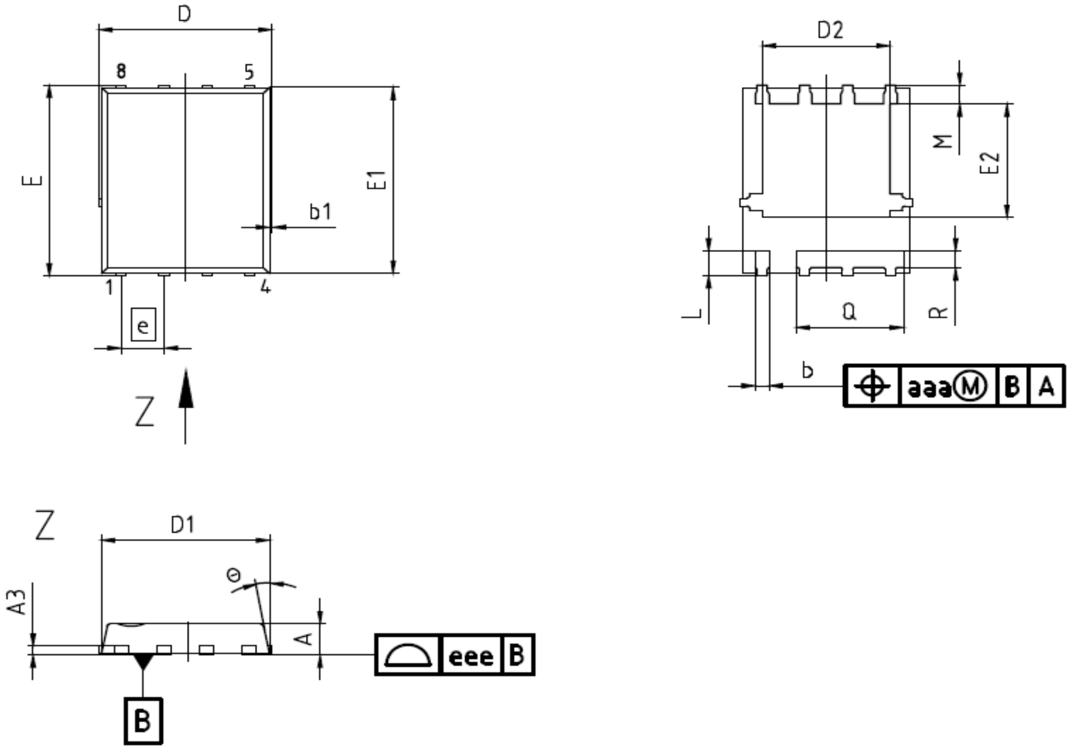


16 Gate charge waveforms



Package Outline **PG-TDSON-8 FL**

PG-TDSON-8 FL: Outline

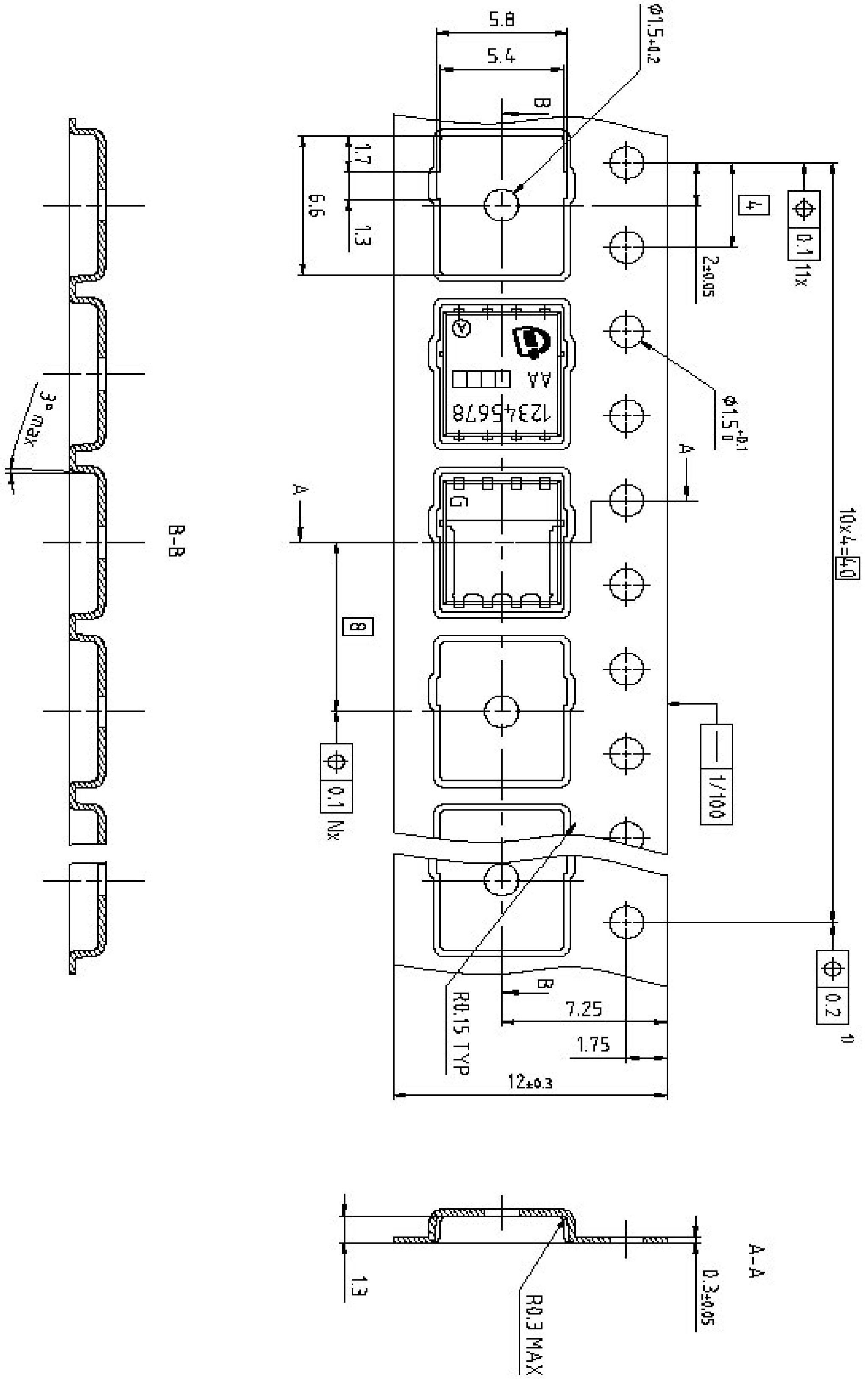


DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	0.90	1.10	0.035	0.043
A3	0.25 (REF)		0.011 (REF)	
b	0.34	0.54	0.013	0.021
b1	0.02	0.22	0.001	0.009
D	5.15 (BSC)		0.203 (BSC)	
D1	5.00 (BSC)		0.197 (BSC)	
D2	3.70	4.40	0.146	0.173
E	6.15 (BSC)		0.242 (BSC)	
E1	6.00 (BSC)		0.236 (BSC)	
E2	3.40	3.80	0.134	0.150
e	1.27 (BSC)		0.050 (BSC)	
N	8		8	
L	0.74	0.84	0.029	0.033
M	0.45	0.66	0.018	0.026
Θ	8.5°	12°	8.5°	12°
Q	3.15	3.25	0.124	0.128
R	0.48	0.58	0.019	0.023
aaa	0.25		0.010	
eee	0.08		0.003	

DOCUMENT NO. Z8B00162237
SCALE 0 2.5 5mm
EUROPEAN PROJECTION
ISSUE DATE 02-08-2011
REVISION 01

Package Outline

PG-TDSON-8: Tape



Dimensions in mm

Published by
Infineon Technologies AG
81726 Munich, Germany

Information

For further information on technology, delivery terms and conditions and prices, please contact the nearest Infineon Technologies Office (www.infineon.com).

Warnings

Due to technical requirements, components may contain dangerous substances. For information on the types in question, please contact the nearest Infineon Technologies Office.

Infineon Technologies components may be used in life-support devices or systems only with the express written approval of Infineon Technologies, if a failure of such components can reasonably be expected to cause the failure of that life-support device or system or to affect the safety or effectiveness of that device or system. Life support devices or systems are intended to be implanted in the human body or to support and/or maintain and sustain and/or protect human life. If they fail, it is reasonable to assume that the health of the user or other persons may be endangered.